

U.S. PATENT DOCUMENTS

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT Sheet 2 of 2**

Docket No. B0004/7080

Applicant: Jochen Franzen

Serial No: 09/778,654

Filed: February 7, 2001

For: GRIDLESS TIME-OF-FLIGHT MASS SPECTROMETER FOR ORTHOGONAL
ION INJECTION

Examiner: Not Yet Assigned

Art Unit: 2881

OTHER PRIOR ART – NON PATENT LITERATURE AND DOCUMENTS

Exam Inits	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the articles (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
ME.		WOLLNIK, H. et al., "Time-of-Flight Mass Spectrometers With Multiply Reflected Ion Trajectories", International Journal of Mass Spectrometry and Ion Processes, 1990., 267-274, Elsevier Science Publishers B.V., The Netherlands.	<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>
			<input type="checkbox"/>

Examiner
Signature

M. El. Shammaa

Date
Considered

11.26.02